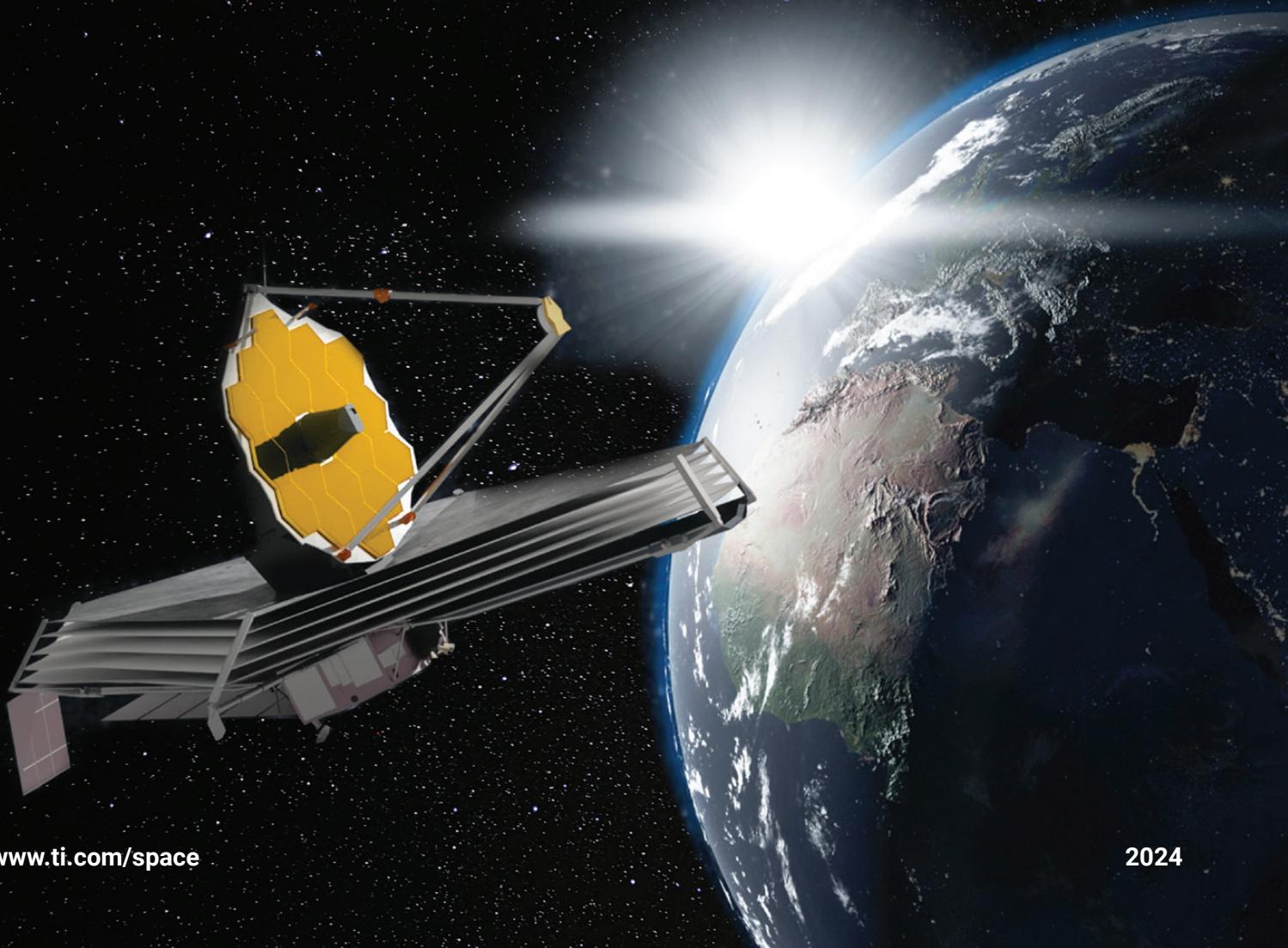


TI Space Products Guide

Radiation-hardened and radiation-tolerant products
to help innovate your space designs



Space Products Guide

Overview/table of contents

TI space products

Our heritage in space applications spans over 60 years, dating as far back as 1958 when the first satellite launched by the U.S., Explorer I, carried aloft radiation detection circuitry using the newly released TI 2N335 silicon-grown junction transistor. From that first satellite, to the first moon landing and first comet landing, to exploring the planets, TI semiconductor devices have been there.

We focus on radiation performance and best-in-class performance products to both our **QMLV/QMLP (typically identified by the -SP suffix)** and **radiation tolerant (identified by the -SEP suffix)** portfolios. The breadth of TI's space portfolio provides a full signal-chain solution. The portfolio includes the smallest RHA point-of-load power solutions, fast discrete SerDes and some of the world's highest performance data converters.

TI's Space products include MIL-PRF-38535 QMLV/QMLP, RHA, and radiation tolerant plastic components. These devices are typically supported with Total Ionizing Dose (TID) and Single Event Effects (SEE) test reports to address potential product degradation in a space environment. The test results for these devices are available in the product folder under the Technical documents tab.

Satellite applications

- Communications payload
- Laser communications payload
- Radar imaging payload
- Optical imaging payload
- Navigation payload
- Scientific exploration payload
- Command & data handling (C&DH)
- Attitude & orbit control system (AOCS)
- Satellite electrical power system (EPS)
- Satellite mechanisms
- Launchers, landers and rovers

TI space products portfolio

TI offers RHA and radiation-tolerant, hermetically packaged components highlighted in each of the red blocks to the right. TI also offers many of these space grade products in die form (known good die or tested die).

For acronyms specific to space terminology, see the end of this document.

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Additional resources

- TI space products and applications: www.ti.com/space.
- Radiation-tolerant portfolio: www.ti.com/SEP.
- The “Radiation Handbook for Electronics” eBook: www.ti.com/RadBook.

Space-grade power management

Featured products

3- to 7-V_{IN}, 18-A, current-mode monolithic point-of-load DC/DC converter

TPS7H4001-SP/TPS7H4003-SEP

Key features

- 0.6V \pm 1.5% V_{REF} accuracy over load, line, temp and TID
- Integrated high-side and low-side power MOSFETs
- Programmable frequency from 100–1000kHz
- Parallel support for 2–4 devices with 180° or 90° Φ shifted SYNC1 and SYNC2 pins (50-kHz master/slave operation)
- Configurable softstart/tracking, external compensation, power good, enable
- Configurable slope compensation
- QML Class-V: 34-pin CDFP, 7.6mm x 21.6mm
- QML Class-P: 44-pin HTSSOP, 6.1mm x 14.0mm
- Space EP: 44-pin HTSSOP, 6.1mm x 14.0mm

Radiation performance

- Rad-hard (RHA) TPS7H4001-SP:
 - TID characterization to 100krad(Si)
 - SEL immunity to 75MeV-cm²/mg at 125°C
- Rad-tolerant TPS7H4003-SEP:
 - TID characterization to 50krad(Si)
 - SEL immune to 43MeV-cm²/mg at 125°C

More information at www.ti.com/product/TPS7H4001-SP

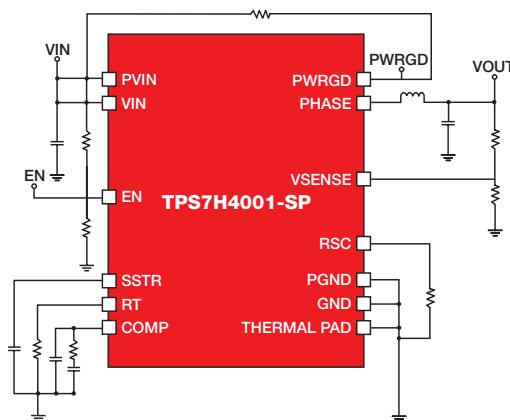
and at www.ti.com/product/TPS7H4003-SEP

Applications

- Space satellite power management and distribution
- Radiation-hardened and tolerant power-tree applications

Benefits

- Higher output current in smaller footprint for powering high-current FPGA and ASIC core voltage rails
- Ease of implementing sequencing schemes
- Easily paralleled for even higher currents with no external components and no external clock needed



1.5V to 7V input 6A eFuse

TPS7H2201-SP/TPS7H2201-SEP

Key features

- On Resistance (RON) of 35mΩ max at V_{IN}=5V at 25°C
- Configurable rise time
- Programmable current limiting and fault timers
- OVP and UVLO
- Low control input threshold enables use of 1.8, 2.5 and 3.3V logic
- QMLV package: 16-pin CDFP, body: 9.6 x 11.0mm
- QMLP & -SEP package: 32-pin HTSSOP, body: 6.1 x 11.0mm

Applications

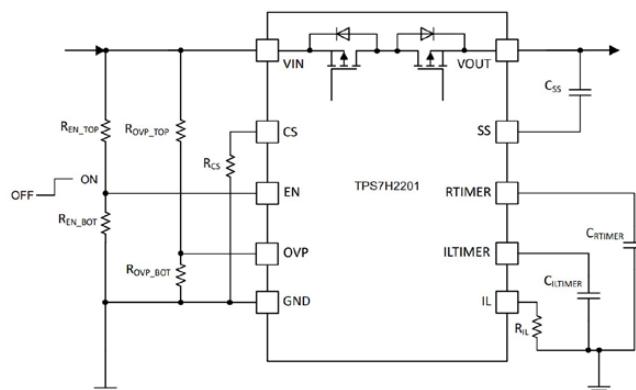
- Space satellite power management and distribution
- Radiation hardened and tolerant power tree applications

Radiation performance

- Rad-hard (RHA) TPS7H2201-SP:
 - TID: 100krad(Si)
 - SEL immune to 75MeV-cm²/mg
- Rad-tolerant TPS7H2201-SEP:
 - TID: 50krad(Si)
 - SEL immune to 43MeV-cm²/mg

Benefits

- Highly integrated solution eliminating the need for discrete FETs for power management
- Controlled inrush current during system power-up
- Reverse current protection for cold sparing applications
- Able to parallel for current sharing and reduced RON
- Low threshold enable compatible with multiple IO standards
- Over current system protection with programmable fault timer



More information at www.ti.com/product/TPS7H2201-SP and at www.ti.com/product/TPS7H2201-SEP

Space-grade power management

Featured products

Radiation-hardened high-speed dual-output current-mode pulse-width modulation controller **TPS7H5001-SP/TPS7H5005-SEP**

Key features

- $0.6V \pm 1\%$ V_{REF} accuracy over load, line, temperature and TID
- Configurable switching frequency from 100kHz to 2MHz.
- External synchronization using SYNC pin
- 5-V outputs, 150mA drive, $R_{OUT} = 15\Omega$
- Synchronous rectification outputs, dead time (PS and SP) and duty cycle limit configurable (leading edge blanking)
- Configurable soft start, EN (UVLO), FAULT (OCP, OVP and OTP) slope compensation and current limit, Hiccup OCP mode
- QML Class-V: 22-pin CDFP, 6.2mm x 7.7mm
- QML Class-P: 24-pin TSSOP, 4.4mm x 7.7mm
- Space EP: 24-pin TSSOP, 4.4mm x 7.7mm

Radiation performance

- Rad-hard (RHA) TPS7H5001-SP:
 - TID characterization to 100krad(Si)
 - SEL immunity to 75MeV-cm²/mg at 125°C
- Rad-tolerant TPS7H5005-SEP:
 - TID characterization to 50krad(Si)
 - SEL immunity to 43MeV-cm²/mg at 125°C

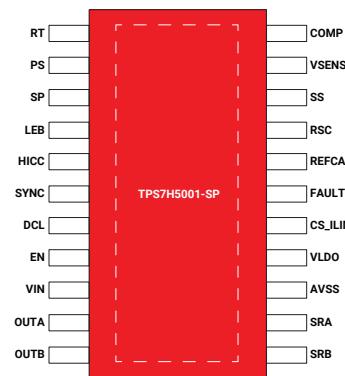
Applications

- Space satellite power management and distribution
- Radiation-hardened and tolerant power tree applications

More information at www.ti.com/product/TPS7H5001-SP and at www.ti.com/product/TPS7H5005-SEP

Benefits

- Support for non-isolated (buck, boost) and isolated (flyback, forward, active clamp, push-pull, half/full-bridge) topologies
- External driver allows support of Si MOSFETs and GaN FETs
- High level of features integration minimizes radiation risks and overall solution size
- Synchronous rectification to enable higher efficiency
- During the cross conduction SET testing, zero events were recorded



4.5 to 14V_{IN}, 12A, current mode POL DC-DC converter

TPS7H4011-SP

Key features

- Integrated high side and low side power MOSFETs
- $0.6V \pm 1\%$ V_{REF} + offset error accuracy over load, line, temperature, and TID
- Configurable high side current limit
- Differential remote sensing capability
- Programmable frequency from 100kHz – 1MHz at 15% accuracy
- Parallel 2 - 4 devices with 90° or 180° phase shifted outputs (100kHz–1MHz freq)
- External input FAULT pin for flexible fault management
- Configurable slope compensation and external OTA compensation
- Adjustable soft-start, power good, and enable for sequencing

Radiation performance

- TID = 100krad(Si) RHA
- SEL immune up to 75MeV-cm²/mg

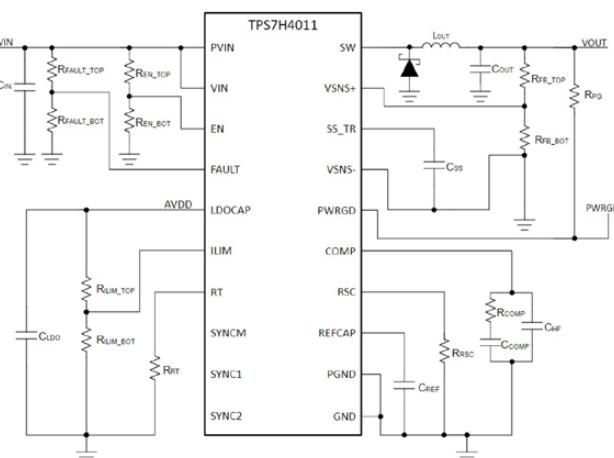
Applications

- Space satellite point of load supply
- Space satellite payloads

More information at www.ti.com/product/TPS7H4011-SP

Benefits

- Wide input voltage range allows for operation directly from 12V distribution rail
- Programmable current limit allows user to optimize overall solution size by tailoring output inductor ratings to application needs
- Differential remote sense allows for voltage drop mitigation that is ideal for low-voltage, high-current applications



Space-grade power management

Featured products

3 to 14V_{IN}, 4 channel sequencer

TPS7H3014-SP

Key features

- Sequence up and down with ability to daisy chain
- Programmable delay from 0.25 to 25ms ($\pm 10\%$ accuracy), or no delay
- Logical input compatible with 1.2V Logic Programmable hysteresis $24\mu\text{A} \pm 3\%$
- Trip Point = $0.6\text{V} \pm 1\%$ (across voltage, temp & radiation)
- Push-Pull EN outputs with external inputs for the pull-up voltage domain

Radiation performance

- TID = 100krad(Si) RHA
- SE/SEFI immune to $75\text{MeV}\cdot\text{cm}^2/\text{mg}$

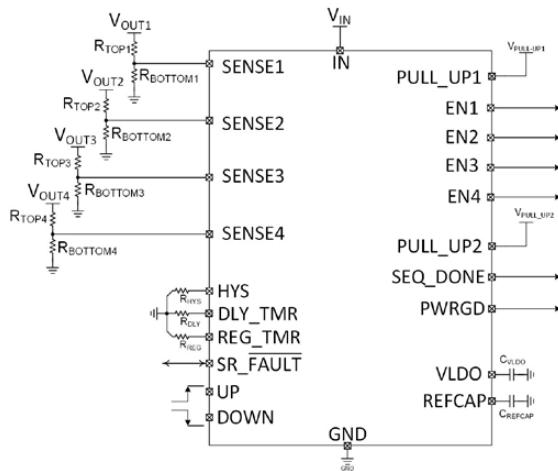
Applications

- Satellite electrical power system (EPS)
- Control sequence and monitoring for complex digital processors such as: FPGAs, SoCs, AFEs, and power systems for space applications

More information at www.ti.com/product/TPS7H3014-SP

Benefits

- Compelling radiation performance support for complex FPGA and ASIC power-up and power-down sequences
- Multiple devices can be cascaded to sequence as many supplies as needed
- Highest accuracy radiation-validated device
- Smallest ceramic solution in the industry



Half-bridge GaN FET gate drivers

TPS7H6003/13/23-SP

Key features

- TPS7H6003-SP V_{IN} 200V, TPS7H6013-SP V_{IN} 60V, TPS7H6023-SP V_{IN} 22V
- V_{IN} = 10 to 14V (8.5V UVLO).
- Integrated 5V LDOs for both high-side and low-side GaN FETs
- f_{SW} \geq 5-MHz, 1.3-A peak source current, 2.5-A peak sink current
- 30-ns typical propagation delay and 5.5-ns typical delay matching
- Split outputs for adjustable turn-on and turn-off times
- Input modes: Independent input mode & PWM input mode

Radiation performance

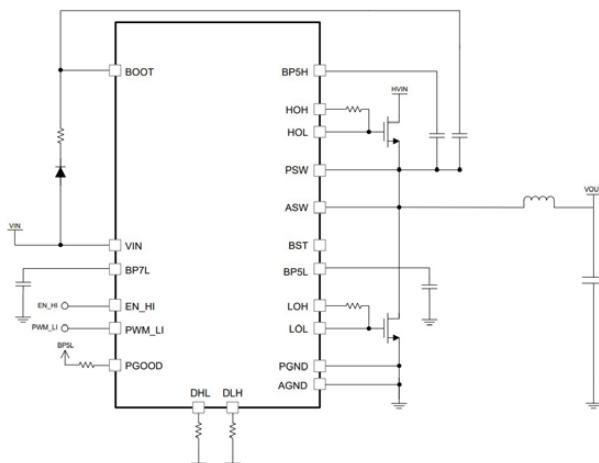
- Total dose (TID) = 100krad(Si) RHA
- SEL immune up to $75\text{MeV}\cdot\text{cm}^2/\text{mg}$

Applications

- Space satellite power supplies
- Communications payload
- Command and data handling
- Optical imaging payload
- Satellite electrical power system

Benefits

- Internal regulator supports GaN applications by properly controlling gate drive voltage
- Dead time configuration in PWM mode allows system optimization in high frequency applications
- Input interlock protection can be enabled or disabled in independent input mode to accommodate multiple converter topologies



More information at www.ti.com/product/TPS7H6003-SP and at www.ti.com/product/TPS7H6013-SP and at www.ti.com/product/TPS7H6023-SP

Space-grade power management

Featured products

0.85V – 7V V_{IN} , 2.2V – 14V V_{BIAS} , 1.5A, low-noise, high PSRR performance LDO

TPS7H1111-SP/TPS7H1111-SEP

Key features

- Ultra-Low Noise: 1.68μ VRMS (10Hz – 100kHz)
- Ultra-low 1/f noise: $100nV/\text{Hz}^{1/2}$ (typ at 10Hz)
- High PSRR: 71dB at 100kHz, 67dB at 1MHz
- V_{OUT} : 0.4V to 5.5V
- Very high accuracy: $\pm 1.5\%$ across line, load, temperature, & radiation
- Low dropout: 200mV (typ) at 1A, 450mV (max) at 1.5A
- Bias supply to minimize power dissipation (Set $V_{BIAS} \geq V_{OUT} + 1.6V$)
- Ability to easily parallel multiple devices for higher output current
- Programmable soft start
- Enable and configurable power good threshold and indicator
- Exposed control loop with the external compensation STAB pin
- Configurable current limit behavior (brick-wall or turn-off)
- QML Class-V: 14-pin CDFP, 8.0mm x 9.1mm
- QML Class-P & -SEP 28-pin HTSSOP, 4.4mm x 9.7mm

Radiation performance

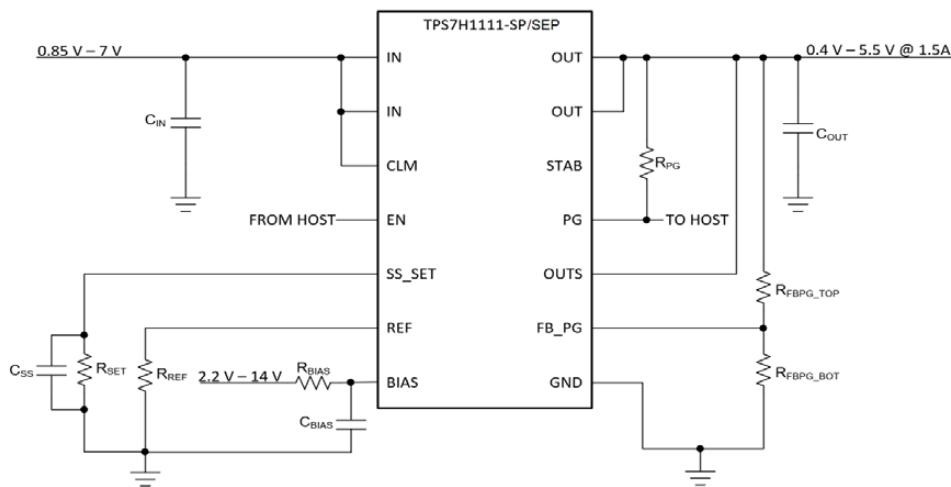
- Rad Hard (RHBD) TPS7H1111-SP:
 - TID (LDR & HDR) = 100krad(Si)
 - SEL/SEB/SEGR immune to $75\text{MeV}\cdot\text{cm}^2/\text{mg}$
 - SET/SEFI characterized to LET = $75\text{MeV}\cdot\text{cm}^2/\text{mg}$
- Rad Tolerant TPS7H1111-SEP:
 - TID characterization to 50krad(Si)
 - SEL/SEB/SEGR immune to $43\text{MeV}\cdot\text{cm}^2/\text{mg}$
 - SET/SEFI characterized to LET = $43\text{MeV}\cdot\text{cm}^2/\text{mg}$

Applications

- Power for high-speed and high-accuracy circuits
 - VCOs (voltage controlled oscillators)
 - Data Converters: ADCs and DACs (analog-to digital and digital-to-analog converters)
 - PLLs (phase-lock-loops), SerDes (serializer and deserializers), Imaging sensors
- Accurate supply for precision ASIC and FPGA supply rails

Benefits

- Lowest noise, highest PSRR LDO in space industry
- Enable full performance of high speed and high precision circuits through clean power supply generation without bulky filters required



More information at www.ti.com/product/TPS7H1111-SP and at www.ti.com/product/TPS7H1111-SEP

Space-grade interface

Featured products

3.3-V CAN transceiver

SN55HVD233-SP/SN55HVD233-SEP

Key features

- Compatible with ISO 11898-2
- Data rates up to 1Mbps
- Extended -7-V to 12-V common mode range
- High-input impedance allows for 120 nodes
- LVTTI I/Os are 5-V tolerant
- Unpowered node does not disturb the bus
- Temperature range: -55°C to 125°C
- Available in 8-pin 6.48 × 6.48-mm ceramic flat pack (HKX)
- Bus pins ESD protection exceeds ±16kV HBM

Radiation performance

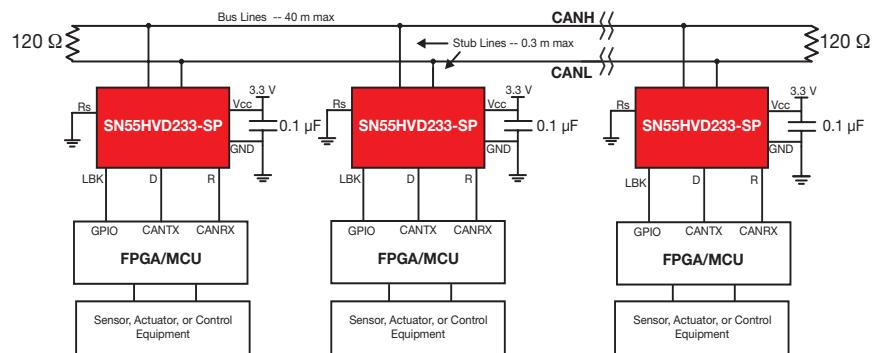
- Rad Hard (RHA) SN55HVD2331-SP:
 - TID = 50krad(Si) RHA
 - SEL immune to 86MeV-cm²/mg
- Rad Tolerant SN55HVD2331-SEP:
 - TID characterization to 30krad(Si)
 - SEL immune to 43MeV-cm²/mg

Applications

- Spacecraft backplane data bus communication and control
- Telemetry/Sensor data transmission
- CAN bus standards such as CANopen, DeviceNet, CAN Kingdom, ISO 11783, NMEA 2000, SAE J1939

Benefits

- RHA qualified and orderable as SMD: 5962L1420901VXC
- Thermal shutdown protection
- Adjustable driver transition times for improved signal quality



More information at www.ti.com/product/SN55HVD233-SP and at www.ti.com/product/SN55HVD233-SEP

3V to 5.5V RS-485 transceiver with flexible I/O supply and IEC ESD

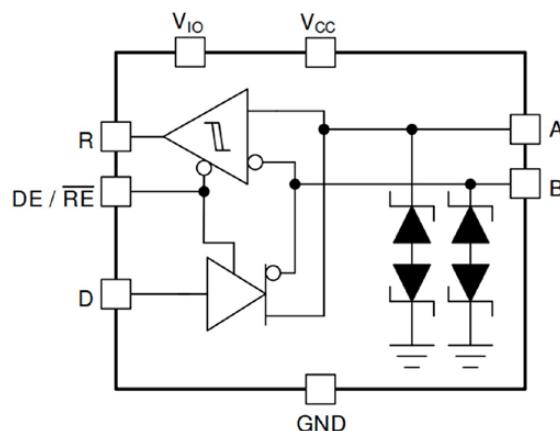
THVD9491-SEP

Key features

- 3V – 5.5V supply voltage (1.65V-5.5V operation support for I/Os)
- Fully integrated system-level EMC protection on bus pins
- ±15kV HBM ESD protection
- Common-mode range: ±12V
- Bus fault protection for DC shorts: ±15V
- Large receiver hysteresis: 250mV
- Data rates up to 12Mbps
- Open, short, and idle bus failsafe receiver
- 1/8th unit load to support up to 256 nodes on a bus

Benefits

- 1.8V – 5V logic supply support eliminates the need for level translator when interfacing with processors with 1.8V I/Os
- Fully integrated IEC ESD, EFT and surge protection – Eliminate system level protection components and reduce system BOM



Radiation performance

- TID = 30krad(Si) RHA
- SEL immune to 43MeV-cm²/mg

Applications

- Low/mid orbit satellite applications

More information at www.ti.com/product/THVD9491-SEP

Space-grade interface

Featured products

Radiation-hardness-assured (RHA), 10/100/1000 Gigabit Ethernet PHY with SEFI monitor **DP83561-SP**

Key features

- TID: 300krad(Si), QMLV-RHA qualified
- SEL immune > 121MeV-cm²/mg at max temp and voltage ratings
- SEU: No link drops and low packet loss up to 48MeV-cm²/mg
- SEFI support suite:
 - Configuration registers protection: ECC corrects SEFI related bit changes
 - PHY state machine monitor: Looks for invalid changes
 - Supply current monitor: Indicates general PHY health to system
 - Interrupt indication for monitors
 - PLL lock monitor
- Operating temperature range: -55 to 125°C
- MAC I/Fs: RGMII, MII
- IEEE 1000Base-T, 100Base-TX, 10Base-T
- 64-pin CFP (11mm × 11mm)

Radiation performance

- TID = 300krad(Si) RHA
- SEL immune to LET = 121MeV-cm²/mg

More information at www.ti.com/product/DP83561-SP

Space-grade data converters

Featured products

Octal, 128-kSPS, simultaneous-sampling 24-bit delta-sigma ADC

ADS1278-SP

Key features

- Simultaneous sampling of 8 inputs via independent 24-bit delta-sigma ADCs capable of converting up to 128kSPS
- Bandwidth: 70kHz
- Signal-to-noise ratio (SNR): 111dB
- Total harmonic distortion (THD): -96 dB (Max.)
- Operating temperature -55 to 125°C
- 84-lead ceramic HFQ 10mm × 10mm

Radiation performance

- TID = 75krad, 50krad(Si) RHA
- SEL immune to LET = 69MeV-cm²/mg (125°C)

Applications

- Orbital observation systems
 - Satellite, shuttles, space stations, launchers
- Satellite sensing and closed-loop control
- Space scientific instrumentation

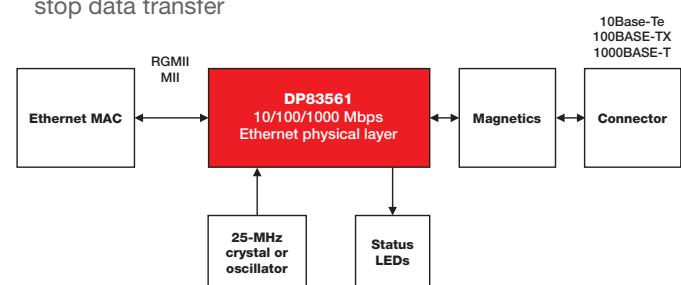
More information at www.ti.com/product/ADS1278-SP

Applications

- Space/satellite communications

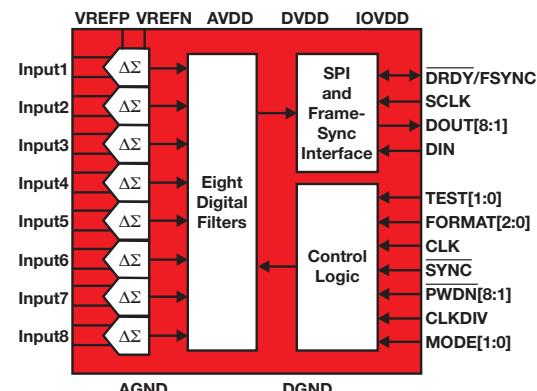
Benefits

- **EMDIO register monitor:** Changes in PHY configuration registers will be indicated to system for action/correction
- **PHY PCS state machine monitor:** Invalid state changes may be indicative of SEFI, system is notified to adjust accordingly
- **Supply current monitor:** SEFI events may cause PHY failure modes undetectable by other method
- **PLL lock monitor:** Loss of lock indication can be used to stop data transfer



Benefits

- Offers easy implementation of simultaneous analog-to-digital conversion for multiple inputs sourced from a wide range of transducers without the need of using an external multiplexer
- Allows accurate measurement of AC signals in the presence of noise; its highly linear transfer function provides high-fidelity and undistorted conversions
- Allows user to better resolve low-level signals found especially in the fields of satellite sensors



Space-grade data converters

Featured products

2-channel, ultra-low power, 0.5 to 65MSPS, 18-bit ADC

ADC3683-SP/ADC3683-SEP

Key features

- Resolution: 18-bit, no missing codes
- Ultra-low power: 50mW/ch (10MSPS), 94mW/ch (65MSPS)
- Noise spectral density: -160dBFS/Hz
- Spectral performance ($f_{IN} = 5\text{MHz}$)
 - SNR: 83.5dBFS
 - SFDR: 87dBc HD2, HD3, SFDR: 99dBFS worst spur
- Analog input bandwidth (-3dB): 400MHz
- Low latency: 1 to 2 clock cycles
- INL/DNL: $\pm 9.0 / \pm 0.7\text{LSB}$ (typ)
- Reference: Integrated or external (buffer integrated)
- Interface: Serial LVDS (SLVDS) – options: 2-, 1-, and 1/2-wire

Radiation performance

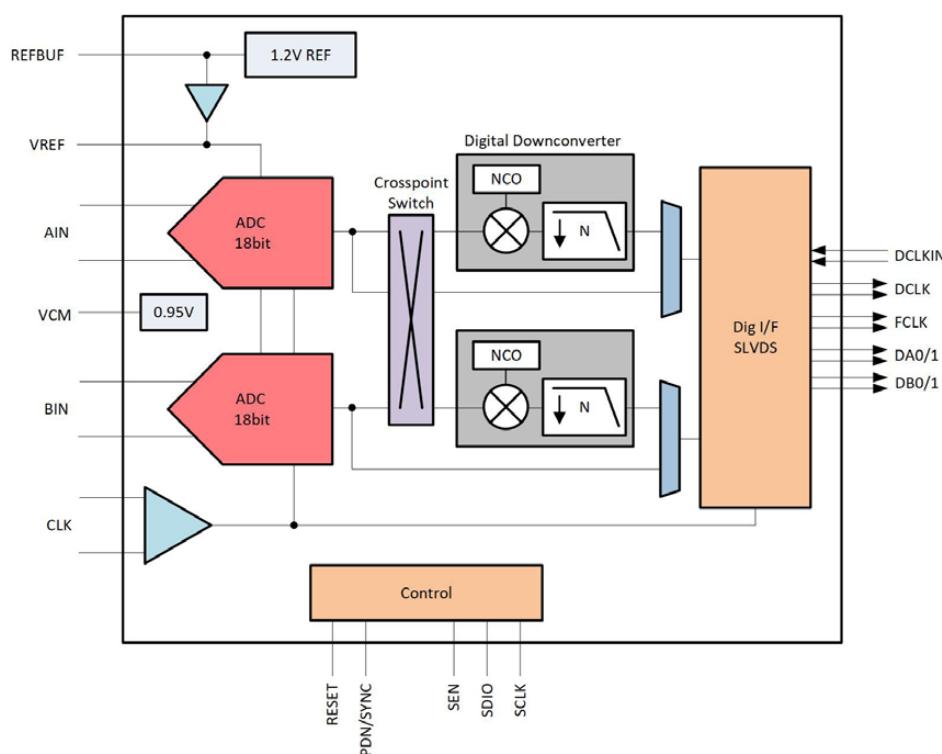
- Rad Hard ADC3683-SP:
 - TID = 300krad(Si) RHA
 - SEL immune to 75MeV-cm²/mg
- Rad Tolerant ADC3683-SEP:
 - TID = 30krad(Si)
 - SEL immune to 43MeV-cm²/mg

Applications

- Narrow band radio/radar
- Precision telemetry
- Satellite optical communications payload
- Satellite imaging payloads

Benefits

- Integrates digital filter options to reduce processing requirements
 - Decimation by 2, 4, 8, 16, or 32, and 32-Bit NCO
- Low latency (1 to 2 clock cycles) for high-speed control loops
- Low offset voltage and offset voltage drift parameters allow for accurate measurements across temperature
- Offers excellent DC precision together with IF sampling support which makes it ideally suited for a wide range of applications
- SLVDS interface minimizes the number of digital interconnects



More information at www.ti.com/product/ADC3683-SP and at www.ti.com/product/ADC3683-SEP

Space-grade data converters

Featured products

12-bit, dual 5.2-GSPS or single 10.4-GSPS ADC

ADC12DJ5200-SP/ADC12DJ5200-SEP

Key features

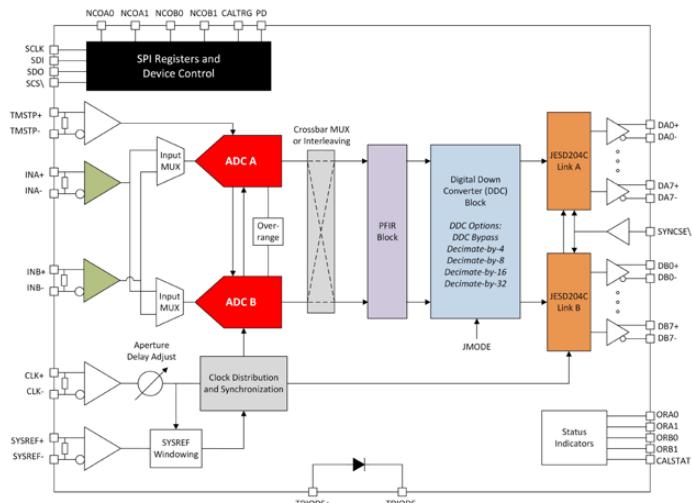
- 12-bit ADC with 8-GHz input bandwidth
- 10.4-GSPS as single, 5.2-GSPS as dual
- Noise Floor: -154.4dBFS/Hz
- ENOB: 8.6 bits
- Easy-to-use synchronization features
- 17.16Gbps JESD204B/C serial data interface
- Optional 4x-32x complex decimation
- Peak RF Input Power (Diff): +26.5dBm
- Programmable FIR filter for equalization
- Power consumption: 4W

Radiation performance

- Rad Hard ADC12DJ5200-SP:
 - TID = 300krad(Si) RHA
 - SEL and SEFI immune to LET > 120MeV-cm²/mg
- Rad Tolerant ADC12DJ5200-SEP:
 - TID characterization to 30krad(Si)
 - SEL immune to 43MeV-cm²/mg at 125°C

Applications

- Wideband Satellite communications (SATCOM)
- RF-sampling software-defined radio (SDR)
- Spectrometry
- RADAR / LIDAR



More information at www.ti.com/product/ADC12DJ5200-SP and at www.ti.com/product/ADC12DJ5200-SEP

16-bit, 2-channel, up to 20.8-GSPS 12-GHz RF digital-to-analog converter

DAC39RF10-SP/DAC39RF10-SEP

Key features

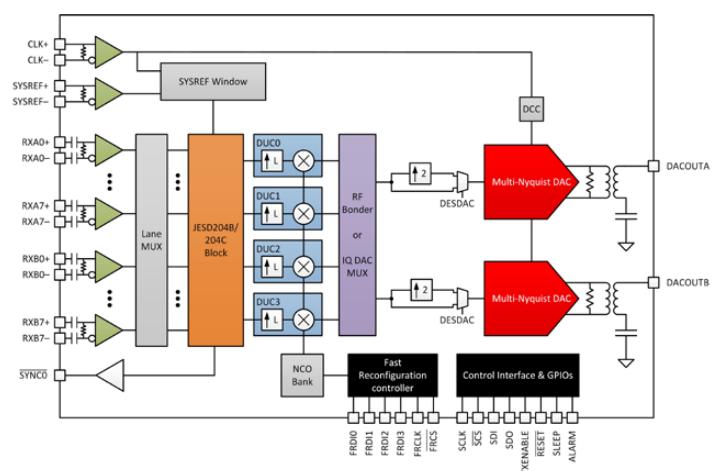
- Sample rate: 10.4GSPS (single edge) and 20.8GSPS (dual edge)
- 16-bits resolution
- Max input rates (real data, 1-ch)
 - 20.8GSPS at 8-bits, 15.52GSPS at 12-bits, 10.4GSPS at 16-bits
- Max input rates (real data, 2-ch)
 - 7.75GSPS at 12-bits, 6.2GSPS at 16-bits
- Output current: 5 - 42mA w/ 7-bit control
- Interface: 16x JESD204C at 12.8Gbps

Radiation performance

- Rad Hard DAC39RF10-SP:
 - TID = 300krad(Si) RHA
 - SEL immune to 120MeV-cm²/mg
- Rad Tolerant DAC39RF10-SEP:
 - TID = 30krad(Si)
 - SEL immune to 43MeV-cm²/mg

Benefits

- Low Phase Noise: -148dBc/Hz at 1GHz/10kHz offset
- DAC Speed & Modes: 2x faster speed, 12GHz+ output
- Digital Up-Converters: 1-256x interpolation, 64-bit NCO phase coherent frequency hopping covering 4x30MHz to 1x5GHz signals
- SERDES Lanes: Lower baud rate, in-package AC caps, & 1mm ball pitch for small PCB size & easier RF routing



Applications

- Satellite Communications (SATCOM)
- Phased array antenna systems
- Synthetic Aperture Radar (SAR) exciter
- Wireless communications testers
- Arbitrary Waveform Generator (AWG)

More information at www.ti.com/product/DAC39RF10-SP and at www.ti.com/product/DAC39RF10-SEP

Eight-channel 12-bit 50-kSPS to 1-MSPS analog-to-digital converter

ADC128S102QML-SP/ADC128S102-SEP

Key features

- Eight input channels
- V_A : 2.7V to 5.25V; V_D : 2.7V to V_A
- 2.3mW with 3-V supply and 0.06 μ W at shutdown
- DNL: -0.5 to +0.9LSB (typ); INL: \pm 0.9LSB (typ)
- SPI digital output
- ADC addressing through CS decoder
- SPI/QSPI/MICROWIRE/DSP compatible
- ADC128S102QML-SP: 16-pin ceramic SOIC, CFP and die
ADC128S102-SEP: 16-pin plastic TSSOP package
(5.0 \times 4.4 mm)

Radiation performance

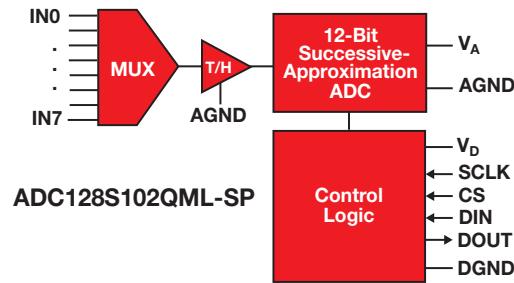
- Rad Hard (RHBD) ADC128S102QML-SP:
 - TID = 100krad(Si) RHA
 - SEL and SEFI immune to LET > 120MeV-cm²/mg
- Rad Tolerant ADC128S102-SEP:
 - TID characterization (ELDRS free) to 30krad(Si)
 - SEL immune to 43MeV-cm²/mg at 125°C

Applications

- Sensors, thermistors, motor control
- Satellite system health, power-supply voltage and current monitoring

Benefits

- Eight sensors can be monitored with one ADC
- All ADC serialized data shares the same input bus to onboard FPGA/ASIC
- Ultra-low power consumption



More information at www.ti.com/product/ADC128S102QML-SP and at www.ti.com/product/ADC128S102-SEP

4-transmit, 6-receive RF-sampling transceiver up to 10.2GHz

AFE7950-SP/AFE7950-SEP

Key features

- Four RF sampling 12GSPS TX DACs
- Six RF sampling 3GSPS RX ADCs
- Maximum RF signal bandwidth: 1200MHz (or 2400MHz for 2TX)
- RF frequency range:
 - TX: 600MHz - 10.2GHz, RX: 5MHz - 10.2GHz
- Digital step attenuators (DSA):
 - TX: 40dB range, 0.125dB steps, RX or FB: 25dB range, 0.5dB steps
- 8 SerDes transceivers up to 24.75Gbps
- Package: 17mm \times 17mm FCBGA, 0.8mm pitch

Radiation performance

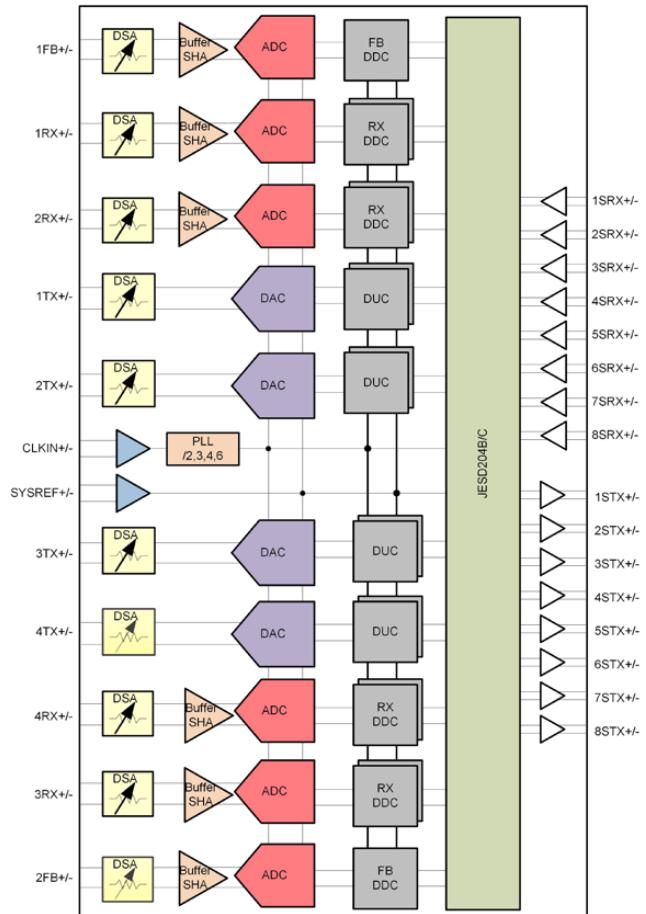
- Rad Hard AFE7950-SP:
 - TID = 100krad(Si) RHA
 - SEL immune to 70MeV-cm²/mg
- Rad Tolerant AFE7950-SEP:
 - TID characterization to 30krad(Si)
 - SEL immune to 43MeV-cm²/mg at 125°C

Applications

- Satellite communications payload downlink
- Satellite telemetry payload downlink

Benefits

- Wide bandwidth multi-channel transceiver
- Direct RF sampling in the L, S, C and X-band frequency ranges
- Density and flexibility enables high-channel count, multi-mission systems



More information at www.ti.com/product/AFE7950-SP and at www.ti.com/product/AFE7950-SEP

Space-grade data converters

Featured products

12-bit telemetry & control – 16 ADC, 12 DAC, and temperature sensor with GPIO

AFE11612-SEP

Key features

- ADC, 12-bit, 16-ch, single-ended or differential options
- DAC, 12-bit, 12-ch, 0 to 5V or 0 to 12.5V
- Temperature sensors
 - Two (2) remote sensors
 - One (1) local/internal sensor
- Internal 2.5V reference
- I²C or SPI interface
- 8 GPIO
- 64-pin plastic HTQFP package (10 x 10mm)

Applications

- Command and data handling (C&DH)
- Communications payload
- Radar imaging payload
- Optical imaging payload
- General analog monitoring and control

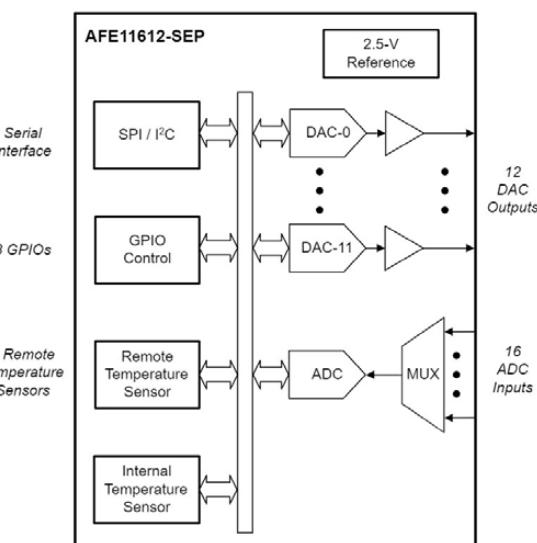
Benefits

- High integration
- Vendor Item Drawing (VID)

More information at www.ti.com/product/AFE11612-SEP

Radiation performance

- TID = 20krad(Si) RLAT
- SEL/SEB/SEGR immune to LET = 43MeV-cm²/mg
- SET/SEFI characterized to LET = 43MeV-cm²/mg



Space-grade amplifiers

Featured products

850-MHz gain bandwidth, rail-to-rail output, negative rail input precision fully differential amplifier

LMH5485-SP/LMH5485-SEP

Key features

- Single channel, fully differential amplifier (FDA)
- Single supply range: 2.7 to 5.4V
- I_Q: 10.1mA
- Power-down current: ~2µA
- Bandwidth: ≈500MHz at G = 2V/V (GBW = 850MHz)
- Input voltage noise: 2.2nV/√Hz,
- THD: -140dBc at 2V_{PP}, 1MHz
- Typical V_{OS}/V_{OS} drift: ±100µV/±0.5µV/°C
- Operating temperature range: -55°C to 125°C

Radiation performance

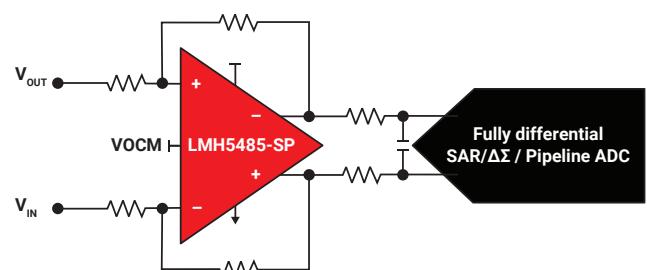
- Rad-hard (RHA) LMH5485-SP:
 - TID characterization to 100krad(Si)
 - SEL immunity to 85MeV-cm²/mg at 125°C
- Rad-tolerant LMH5485-SEP:
 - TID characterization to 30krad(Si)
 - SEL immune to 43MeV-cm²/mg at 125°C

Applications

- SE to DE
- ADC driver
- Narrow-band radar

Benefits

- Low offset voltage and offset voltage drift parameters allow for accurate measurements across temperature
- Offers excellent DC precision together with IF sampling support which makes it ideally suited for a wide range of applications
- Supports single-ended to differential conversion
- RLAT to 100-krad qualified for GEO applications



More information at www.ti.com/product/LMH5485-SP
and at www.ti.com/product/LMH5485-SEP

Space-grade amplifiers

Featured products

Four-channel, 11-MHz gain bandwidth, low-noise ($5.1\text{nV}/\sqrt{\text{Hz}}$), rail-to-rail output precision (120 μV) junction FET operational amplifier

OPA4H014-SEP

Key features

- Gain bandwidth 11MHz
- Slew rate 20V/ μs
- Input stage offset voltage 20 μV (max)
- Offset voltage drift 1 $\mu\text{V}/^\circ\text{C}$ (max)
- Input bias current 10pA (max)
- Supply current 1.8mA (typ)
- Input stage voltage noise 5.1nV/ $\sqrt{\text{Hz}}$ at 1kHz
- Current noise 0.8 fA/ $\sqrt{\text{Hz}}$ at 1kHz
- 0.1-Hz to 10-Hz noise 250nV_{pp}
- 14-pin plastic package – TSSOP (PW) (5.0mm × 4.4mm)

Radiation performance

- TID characterization (ELDRS free) to 30krad(Si)
- SEL immune to 43MeV·cm²/mg at 125°C

Applications

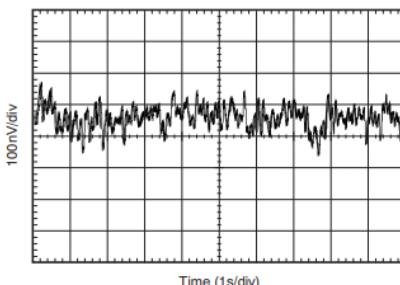
- Sensors
- Thermistors
- Instrumentation
- Telemetry/monitoring

More information at www.ti.com/product/OPA4H014-SEP

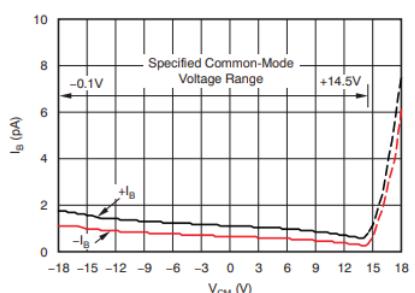
Benefits

- High accuracy, stability over full military temperature range
- Precision JFET provides better matching to high-impedance sources such as sensor outputs and very-low-input bias current
- Low total noise (voltage and current) enables a wide range of input impedance sources for minimal error contributions
- Better matching to high-impedance sources such as sensor outputs
- RLAT to 30-krad qualified for new space LEO applications

0.1-Hz to 10-Hz Voltage Noise



Low input bias across V_{cm} range



12-V, quad femtoampere bias current, precision rail-to-rail input/output operational amplifier

LMP7704-SP

Key features

- Ultra-low input bias current: $\pm 500\text{fA}$ (typ)
- Low offset voltage: $\pm 260\mu\text{V}$ (max)
- +2.7-V to +12-V supply operation
- Rail-to-rail input and output
- Unity gain bandwidth: 2.5MHz
- Input voltage noise: 9nV/ $\sqrt{\text{Hz}}$
- Supply current: 725 $\mu\text{A}/\text{ch}$
- Package: 14-lead CFP, 9.9mm × 6.35mm

Radiation performance

- TID = 100krad(Si) RHA
- SEL = 85MeV·cm²/mg (125°C)

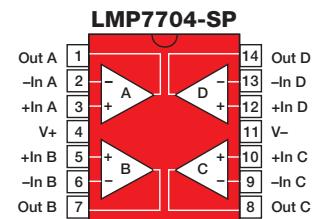
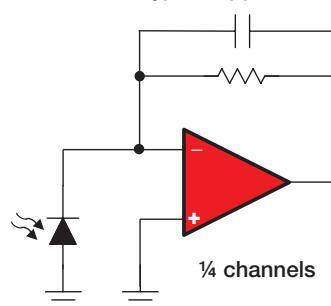
Applications

- Precision transimpedance amplifier for satellite telemetry
- High-impedance satellite sensor interface
- High-gain amplifiers

Benefits

- RHA qualified
- Exceptional DC performance with lowest bias current available for space applications
- Unity gain stable operation
- Rail-to-rail with precision allows single op amp for most board applications

Typical application



More information at www.ti.com/product/LMP7704-SP

Space-grade amplifiers

Featured products

Quad, 40-V 4.5-MHz rail-to-rail input and output operational amplifier

OPA4H199-SEP

Key features

- Low offset voltage: $\pm 125\mu V$
- Low noise: $10.8nV/\sqrt{Hz}$ at 1kHz
- High common-mode rejection: 130dB
- Low bias current: $\pm 10pA$
- Rail-to-rail input and output
- Wide bandwidth: 4.5MHz GBW
- High slew rate: $21V/\mu s$
- High capacitive load drive: $1nF$
- MUX-friendly/comparator inputs
- Low quiescent current: $560\mu A$ per amplifier
- Wide supply: $\pm 1.35V$ to $\pm 20V$, $2.7V$ to $40V$
- Robust EMIRR performance: EMI/RFI filters on input and supply pins)

Radiation performance

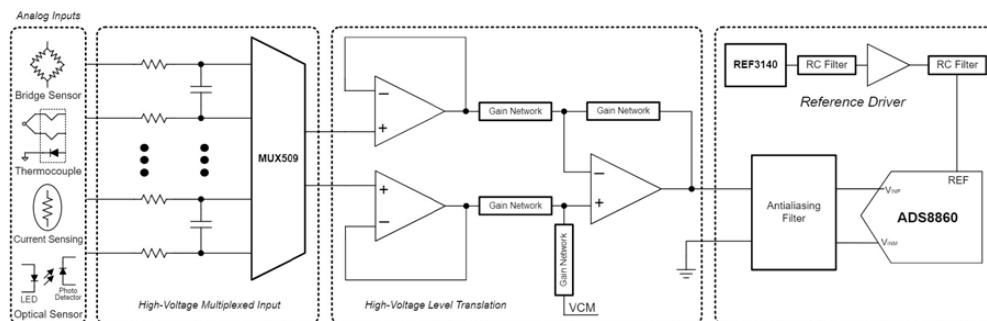
- TID characterization to 30krad(Si)
- SEL immune to $43MeV\cdot cm^2/mg$ at $125^\circ C$

Applications

- Support low earth orbit space applications
- Space sensor and control (telemetry)
- Satellite electrical power system (EPS)
- Flight control
- Satellite command & data handling
- Satellite payloads

Benefits

- Broadest supply voltage (2.7 - 40-V) rail-to-rail input and output support offers exceptional flexibility in a range of applications
- Smallest Radiation Tolerant, 4-ch op amp in the industry
- Low offset voltage and offset voltage drift parameters allow for accurate measurements across temperature
- Low noise and THD+N enables audio/high-gain configurations
- Strong output current and cap load drive with low settling time ideal for ADC applications



More information at www.ti.com/product/OPA4H199-SEP

High common-mode Voltage ($\pm 120V$) difference amplifier

INA1H94-SP

Key features

- Common-mode volt. range: $\pm 120V$
- CMRR (minimum): 90dB
- VOS/VOS drift: $1.1mV/15\mu V/^\circ C$
- Max. gain error: 0.02%
- Max. gain error drift: $10ppm/^\circ C$
- Max. gain non-linearity: 0.001% FSR
- Bandwidth: 500kHz
- Slew rate: $5V/\mu s$ (typ)
- Supply current: 0.9mA (max)

Radiation performance

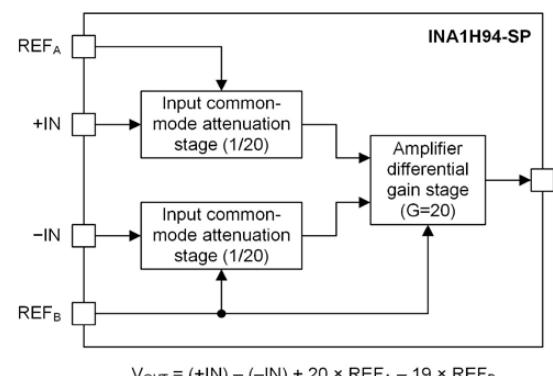
- TID = 100krad(Si) RHA
- SEL = $75MeV\cdot cm^2/mg$ at $125^\circ C$

Applications

- HV current sensing
- Battery cell voltage monitor
- Motor sensingr

Benefits

- Accurately measure small differential voltages in the presence of common-mode signals up to $\pm 275V$
- In many applications, where galvanic isolation is not required, the INA1H94-SP can replace isolation amplifiers



More information at www.ti.com/product/INA1H94-SP

Space-grade clocks and timing

Featured products

15-GHz low-noise wideband phase-locked loop with integrated voltage-controlled oscillation **LMX2615-SP/LMX2694-SEP**

Key features

- Space grade 40-MHz to 15-GHz wideband synthesizer with phase synchronization and JESD204B support
- $-110\text{dBc}/\text{Hz}$ closed-loop phase noise at 100kHz offset at 15-GHz carrier frequency
- 45-fs RMS jitter at 8 GHz (100Hz to 100MHz)
- Ability to synchronize output phase with OSCin
- > 50 fixed-pin programmable options
- Single 3.3-V supply
- $11 \times 11\text{mm}^2$ 64-lead CQFP ceramic package

Radiation performance

- Rad-hard (RHA) LMX2615-SP:
 - TID = 100krad(Si) RHA
 - SEL/SEU immune to LET = $120\text{MeV}\cdot\text{cm}^2/\text{mg}$ (125°C)
- Rad-tolerant LMX2694-SEP:
 - TID characterization to 30krad(Si)
 - SEL/SEU immune to LET = $43\text{MeV}\cdot\text{cm}^2/\text{mg}$ (125°C)

Applications

- Space communications
- Space radar systems
- Phased-array antennas and beam forming

More information at www.ti.com/product/LMX2615-SP and at www.ti.com/product/LMX2694-SEP

JESD204B clock generator and jitter cleaner **LMK04832-SP/LMK04832-SEP**

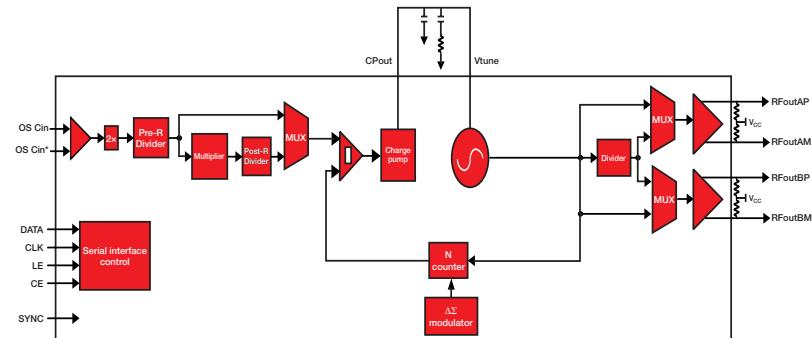
Key features

- Supports 7 JESD204B targets (7 device clock and 7 SYSREF) or 14 differential output clocks
- Dual-loop platinum PLL architecture
- 54-fs RMS jitter at 2.5GHz, 61-fs RMS jitter at 3.2GHz (12kHz–20MHz)
- Noise floor $-156.5\text{dBc}/\text{Hz}$ at 3200MHz
- CML swing: 1.2V_{PP} differential at 3.2GHz
- 2 integrated VCO to support 2 independent frequency plans
 - VCO0 = 2440 to 2580MHz
 - VCO1 = 2945 to 3255MHz
- 320-MHz PLL2 maximum phase detector frequency
- $-230\text{ dBc}/\text{Hz}$ PLL2 FOM and $-128\text{ dBc}/\text{Hz}$ PLL2 1/f
- SYSREF analog delay 25-ps step resolution
- 0-delay mode for either dual loop or single loop
- JESD204B sourced from distribution or clock generation mode/Hz
- Holdover mode when input clock is lost
- Rad Hard: 64-pin ceramic with nonconductive tie bar
- Rad tolerant: 64-pin PAP0064E, 10mm x 10mm

More information at www.ti.com/product/LMK04832-SP and at www.ti.com/product/LMK04832-SEP

Benefits

- Wideband clock source to generate any clock frequency for high-speed data converters
- Support for generating or repeating SYSREF compliant to JESD204B standard
- Save board space and complexity by replacing discrete components with LMX2615
- High-performance PLL can attain very low in-band noise and integrated jitter

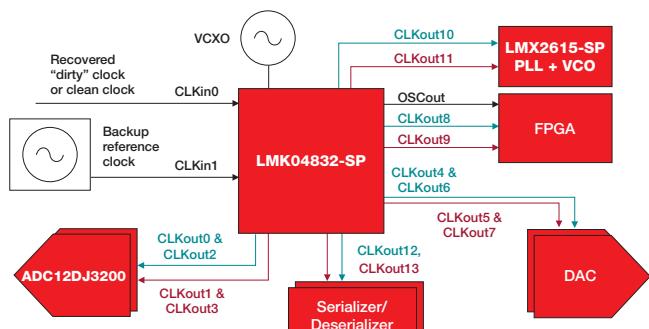


Radiation performance

- Rad-hard (RHA) LMK04832-SP:
 - TID characterization to 100krad(Si)
 - SEL immunity to $120\text{MeV}\cdot\text{cm}^2/\text{mg}$ at 125°C
- Rad-tolerant LMK04832-SEP:
 - TID characterization to 30krad(Si)
 - SEL immune to $43\text{MeV}\cdot\text{cm}^2/\text{mg}$ at 125°C

Applications

- Low jitter noise with JEDEC JESD204B
- Space communications
 - JESD204B clocking systems



Space-grade clocks and timing

Featured products

15GHz buffer, multiplier and divider with SYSREF and FPGA clock LMX1906-SP/LMX1860-SEP

Key features

- Up to 15GHz output frequency
 - SYSREF and SYNC features work with up to 12.8GHz input
- Noise Floor of -158dBc/Hz for a 6GHz output
- 4 high frequency clock outputs
 - Can be used as a buffer, divider (divide by 2, 3, 4, 5, 6, 7 or 8) or multiplier (x2, x3, x4)
- 1 LOGICLK Output for FPGA clocking
 - Includes divider values of 1, 2, 3, ... up to 1023
- SYSREF paired with each clock output
 - Individual delay adjustment
 - Supports both master and repeater mode
- SYSREF Windowing optimizes setup and hold times of SYSREFREQ

Radiation performance

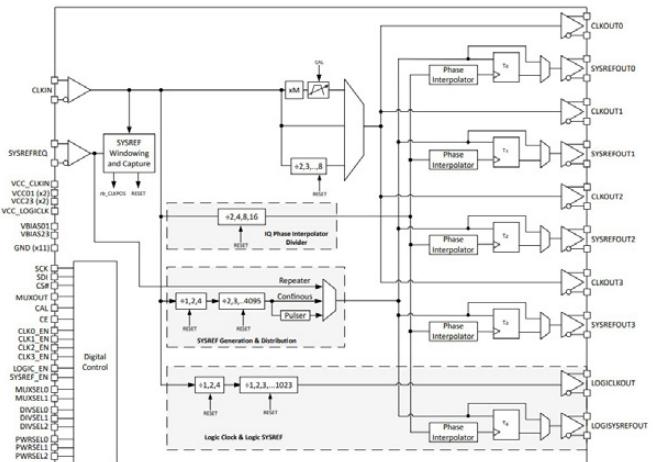
- Rad-hard (RHA) LMX1906-SP:
 - TID = 100krad(Si) RHA
 - SEL/SEU immune to LET = 120MeV-cm²/mg (125°C)
- Rad-tolerant LMX1860-SEP:
 - TID characterization to 30krad(Si)
 - SEL/SEU immune to LET = 43MeV-cm²/mg (125°C)

Applications

- Radar imaging payload
- Communications payloads
- Command and data handling
- Data converter clocking
- Clock distribution/multiplication/division
- multiplication/division

Benefits

- High integration reduces components & improves skew variation
- Low noise floor minimizes clock degradation of data converter SNR
- Pin modes for easy device configuration without SPI – power, divider, mux selection and output EN



More information at www.ti.com/product/LMX1906-SP and at www.ti.com/product/LMX1860-SEP

Space-grade microcontrollers

Featured product

16-MHz ultra-low-power microcontroller with ferroelectric RAM and 40 inputs/outputs

MSP430FR5969-SP

Key features

- Extremely low power consumption 16-bit RISC architecture:
 - 100µA/MHz active
 - 0.02µA shutdown, 0.4µA standby
- 64KB of non-volatile, ferroelectric RAM (FRAM)
- Integrated peripherals for system housekeeping, telemetry
 - Real-time clock (RTC)
 - Five 16-bit timers
 - 16-channel analog comparator
 - 12-bit analog-to-digital converter (ADC) with 16 inputs, internal reference and sample-and-hold
 - Serial interfaces supporting UART, SPI, I²C
 - Multi-function I/O ports
- Support for 32-kHz crystals or internal clock sources
- 48-pin VQFN and TQFP plastic packages for reduced size/weight

Radiation performance

- TID = 75krad(Si), 50krad(Si) RHA
- SEL immune to LET = 72MeV-cm²/mg

Applications

- Spacecraft distributed telemetry and housekeeping
- Sensor management and data logging
- Satellite remote terminal units

Benefits

- Reduced SWaP needed for system housekeeping functions
- Housekeeping/telemetry can be offloaded from FPGA
- Reusable RTU architecture across subsystems

MSP430FR5969-SP

Ultra-low power 16-bit MCU	64-KB FRAM
16 MHz	Watch dog timer, Timer 0_A3, Timer 1_B3, Timer 2_A3, Timer 3_B3, Timer 4_B3
Real-time JTAG, Embedded emulation, BSL	2 UARTs or SPI 1 I ² C or SPI
32×32 Multiplier DMA (3 ch), CRC16	Up to 3 1×8 + 1 1×3 I/O ports w/ interrupts / wake up
Comp_D / Vref ADC12 (up to 16 ch)	Power-on reset Brown-out reset XT1, VLO DCO ($\pm 2\%$), Real-time clock

More information at www.ti.com/product/MSP430FR5969-SP

Space-grade microcontrollers

Featured products

Radiation Tolerant, Hercules™ ARM® Cortex®-R5F MCU TMS570LC4357-SEP

Key features

- Space enhanced plastic
 - Controlled baseline, one fabrication site, one assembly/test site
 - Gold Au wire
 - Available in extended (-55°C to 125°C) temperature range
 - Extended product life cycle & extended product-change notification
 - Product traceability
 - Enhanced mold compound for low outgassing
- High-performance microcontroller with advanced fault detection, safety-critical applications
 - Lockstep Arm® Cortex-R5F CPUs at 300MHz with ECC-protected caches, ECC on Flash and RAM interfaces
 - Built-in self-test (BIST) for CPU, high-end, timers, and on-chip RAMs
 - Error Signaling Module (ESM) with error pin
 - Voltage and clock monitoring, 3 temperature sensors on die
 - 4MB on-chip flash
- Advanced integration & networking
 - 10/100 ENET, CAN, SPI, I²C, UART interfaces
 - 2x high-end timers (N2HET), 2x A12-bit ADCs, enhanced timing peripherals
 - Up to 145 GPIOs

Radiation performance

- TID characterization (ELDRS free) to 30krad(Si)
- SEL immune to 43MeV·cm²/mg at 125°C

More information at www.ti.com/product/TMS570LC4357-SEP

Space-grade sensor products

Featured products

Very wide common voltage current-sense amplifier with split stage for filtering INA901-SP

Key features

- -15-V to 65-V common-mode range independent of supply
- 2.7-V to 16-V supply
- Split stages for filtering
- Bandwidth up to 130kHz
- Gain: 20V/V
- Package: Ceramic 8-lead HKX 6.5mm × 6.5mm

Radiation performance

- TID = 50krad(Si) RHA
- SEL immune to LET = 75MeV·cm²/mg

Applications

- Current monitor for current-mode control DC/DC converter
- Current measurement in an H-Bridge for motor control
- Latching current limiters on high common-mode bus
- Current sensing on GaN modules for increased efficiency

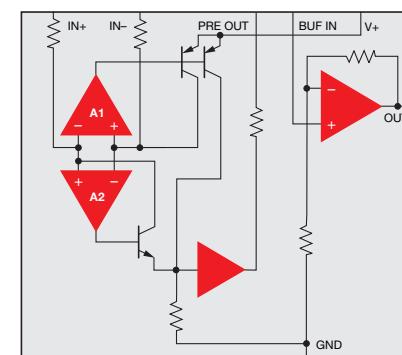
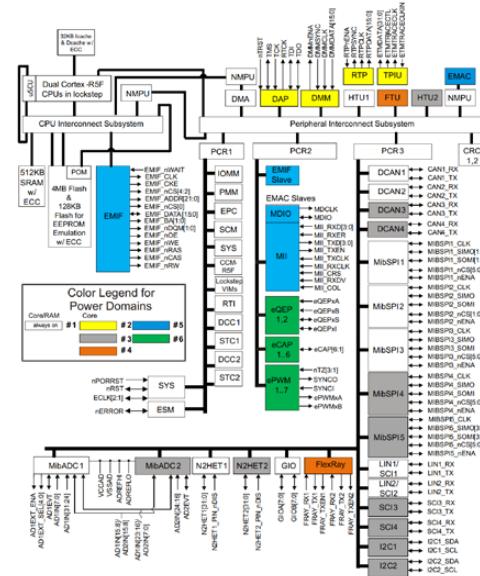
More information at www.ti.com/product/INA901-SP

Applications

- Spacecraft distributed processing
- Sensing & control

Benefits

- Radiation Lot Acceptance Testing (RLAT) to 20krad(Si)
- Vendor Item Drawing (VID) TBD
- Lockstep ARM Cortex-R based MCU – with up to 500 peak DMIPS and 128KB to 4MB flash memory
- Flexible communication and control – Ethernet, Flexray, CAN. Up to 84 timer and 41 12-bit ADC channels



Benefits

- Eliminates need for additional protective components in the event of CMR reversals
- Preserves buffered voltage output and saves using an additional op amp
- Simplifies design of current control loops
- Enables a flexible circuit design
- Orderable as SMD: 5962L1821001VXC

Space-grade sensor products

Featured products

Remote and local digital temperature sensor with QMLV, QMLP, and radiation tolerant variants

TMP461-SP, TMP9R01-SP, TMP9R01-SEP

Key features

- Enables measurement of remote diode temperatures in the range of -64°C to 191°C
- Programmable calibration registers
- Remote diode temperature sensor accuracy: $\pm 1.5^{\circ}\text{C}$
- Local temperature sensor accuracy: $\pm 2^{\circ}\text{C}$
- Accuracy post calibration : $\pm 0.1^{\circ}\text{C}$
- Supply and logic voltage range: 1.7V to 3.6V
- 35- μA operating current (1 SPS), 3- μA shutdown current

Radiation performance

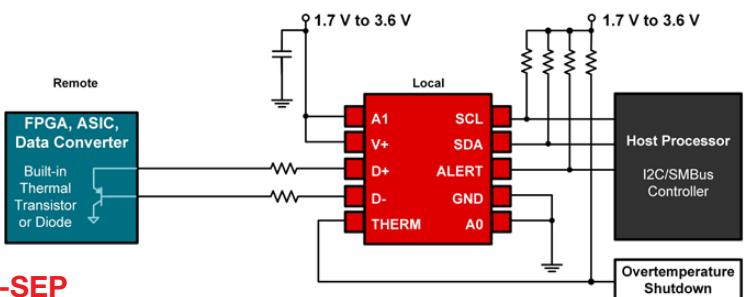
- TMP461-SP (QMLV) and TMP9R01-SP (QMLP)
 - TID = 100krad(Si) RHA
 - SEL Immune to LET = 75MeV- cm^2/mg
- TMP9R01-SEP (Radiation Tolerant)
 - TID Characterization = 50krad(Si)
 - TID RLAT/RHA = 30krad(Si)
 - SEL Immune to LET = 43MeV- cm^2/mg

Benefits

- RHA and radiation tolerant versions available
- Available in ceramic package with thermal pad, as well as a small VSSOP with 3mm x 3mm body size.
- Supports measurements of integrated thermal diode in FPGAs and ASICs, as well as discrete diodes for accurate temperature monitoring.

Variants

- **TMP461-SP** – QMLV-RHA, 100krad(Si), 76MeV
- **TMP9R01-SP** – QMLP-RHA, 100krad(Si), 76MeV
- **TMP9R01-SEP** – Rad Tolerant, 50krad(Si), 43MeV



More information at www.ti.com/product/TMP9R01-SEP

also see www.ti.com/product/TMP461-SP and www.ti.com/product/TMP9R00-SP

Space-grade logic products

Featured products

Space CMOS Logic Family

SN54SCxT-SEP

Key features and benefits

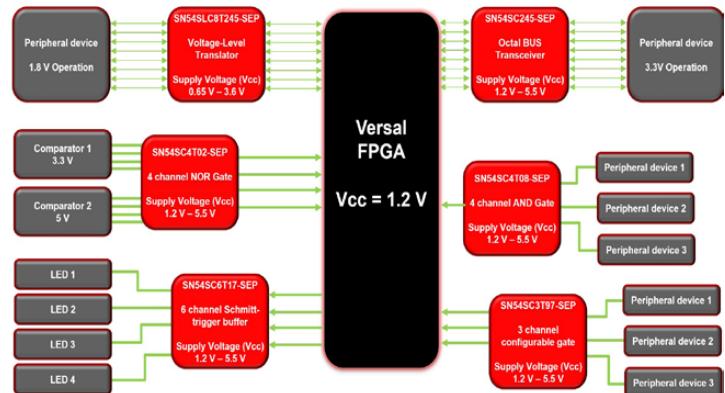
- Wide supply voltage range of 1.2V to 5.5V, enabling compatibility with modern FPGAs
- SCxT enhanced input voltage enables single-supply voltage translation
- Supports $\pm 24\text{mA}$ continuous output drive at 5V
- Fast operation with typical propagation delays (tpd) near 10ns
- SEU/SET Immune Latches (43MeV LETEFF)
- Built-in triple redundancy feature for Latches, Flip-Flops, and Shift Registers
- Configurable multi-function gates enable design flexibility (SC3T97 & SC3T98)

Applications

- Power sequencing
- Fault control and detection
- Driving signals across long board traces and transmission lines
- Single or dual supply level translation
- System reset and redundancy

Radiation performance

- TID = 30-50krad(Si)
- SEL immune to LET = 43MeV- cm^2/mg



- 7 logic gates: NAND, NOR, AND, OR, XOR, Config1, Config2
- 5 buffers/inverters: 3-state w/output enable, Schmitt-trigger, open-drain
- D-type flip-flop
- Octal BUS transceiver
- Dual supply level translator
- Serial-in, parallel-out shift register
- 3-line to 8-line decoder/demultiplexer

More information at www.ti.com/product/SN54SCxT-SEP

Space-grade data converters (cont'd)

High-Speed DACs (>10MSPS)

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² /mg)	Res. (Bits)	# of Ch	Update Rate (Max) (MSPS)	Settling Time (Typ) (ns)	SNR (dB)	SFDR (dBc)	THD (dBc)	Interpolation	Power (Typ) (mW)	Architecture	Interface	Pkg. Group	ECCN ²
DAC5670-SP	5962-07247	QMLV	100	–	–	14	1	2400	3.5	52	55	52	1x, 2x	2000	Current Sink	Parallel LVDS	CBGA	–
DAC5675A-SP	5962-07204	QMLV	100	–	109	14	1	400	12	67	82	70	None	660	Current Sink	Parallel LVDS	CQFP	EAR99 [†]
DAC39RF10-SP	–	SHP-RHA	300	300	120	16	2	20800	36	–	85	–	128x, 12x, 16x, 192x, 1x, 24x, 256x, 2x, 32x, 3x, 48x, 4x, 64x, 6x, 8x, 96x	3800	Current Source	JESD204B, JESD204C	FCBGA	–
DAC39RFS10-SP	–	SHP-RHA	300	300	120	16	1	20800	36	–	85	–	128x, 12x, 16x, 192x, 1x, 24x, 256x, 2x, 32x, 3x, 48x, 4x, 64x, 6x, 8x, 96x	2800	Current Source	JESD204B, JESD204C	FCBGA	–

[†]EAR99 only pertains to certain device variants, including the Engineering Model (DAC5675AHFG/EM) and one Flight Model variant (5962-0720402VXC).

For up-to-date ECCN information please email: gic_eccn-hits-naftateam@list.ti.com

Analog Front Ends: CCD/CIS Imaging

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² /mg)	# of Ch	Resolution (Bit)	Sampling Rate (MSPS)	PGA Range (dB)	Fine Offset DAC Range (mV)	Power per Channel (mW/Ch)	Package	ECCN ²
LM98640QML-SP	5962-18203	QMLV-RHA	100	100	120	2	14	5 to 40	-3 to 18	±5	122	CQFP	EAR99

Space-grade clocks and timing

RF PLLs and Synthesizer

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² /mg)	Normalized PLL Phase Noise (dBc/Hz)	1/f Noise (10-kHz Offset at 1-GHz Carrier) (dBc/Hz)	Output Frequency (Min) (MHz)	Output Frequency (Max) (MHz)	Supply Voltage (V)	Features	Package Body Size – W × L (mm ²)	Package Group	ECCN ²
LMX2615-SP	5962-17236	QMLV	100	100	120	–236	–129	40	15200	3.2 to 3.45	JESD204B	10.90 × 10.90	CQFP	EAR99
LMX1906-SP	5962-23202	QMLV-RHA	100	–	87	–159	–161	300	15000	2.4 to 2.6	JESD204B/C	10.00 × 10.00	HTQFP	EAR99

Clock Jitter Cleaners

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² /mg)	# of In	# of Out	RMS Jitter (fs)	Output Freq. (Min) (MHz)	Output Freq. (Max) (MHz)	Supply Voltage (V)	Input Type	Output Type	Package Group	ECCN ²
CDCM7005-SP	5962-07230	QMLV	100	–	60	2	5	–	0	1500	3.0 to 3.6	LVC MOS (REF_CLK), LVPECL (VCXO_CLK)	LVC MOS, LVPECL	CQFP	EAR99
LMK04832-SP	5962-17237	QMLV-RHA	100	100	120	3	15	54	0.305	3255	3.135 to 3.465	LVC MOS, LVDS, LVPECL	CML, LVPECL, LCPECL, HSDS, LVDS, LVC MOS	CQFP	EAR99

Clock Buffers

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² /mg)	Additive RMS Jitter (Typ) (fs)	Output Freq. (Max) (MHz)	Number of Outputs	Output Skew (ps) (MHz)	Supply Voltage (V)	Input Type	Output Type	Package Body Size – W × L (mm ²)	Package Group	ECCN ²
CDCLVP111-SP	5962-16207	QMLV	75	–	69	40	3500	10	50	2.375 to 3.8	CML, LVDS, LVPECL, SSTL	LVPECL	9.078 × 9.078	CQFP	EAR99

Timers

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² /mg)	V _{CC} Range (V)	Output Level	Package	ECCN ²
SE555-SP	5962-98555	QMLV	25	–	Bipolar	4.5 to 16.5	TTL	CDIP	EAR99

¹All device operating temperatures are –55 to +125°C.

²ECCN information for products that are EAR99 are shown. For up-to-date ECCN information on any product, please email: gic_eccn-hits-naftateam@list.ti.com.

Space EP (cont'd)

RF Differential Amplifiers

Part Number	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT/ RHA	SEL (MeV•cm ² / mg)	Min Freq (GHz)	Max Freq (GHz)	Diff Voltage Swing (Vpp)	Supply Voltage (V)	P1dB at 2GHz (dBm)	Gain at 2GHz (dB)	OIP3 at 2GHz (dBm)	NF at 2GHz (dB)	Available Packages	ECCN ¹
TRF0208-SEP	V62/TBD	TI Space EP	30	30	43	0.01	11	2	3.3	15	16	37	6.8	QFN	EAR99

¹ECCN information for products that are EAR99 are shown. For up-to-date ECCN information on any product, please email: gtc_eccn-hts-naftateam@list.ti.com.

Integrated Precision ADC and DAC

Part Number	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT/ RHA	SEL (MeV•cm ² / mg)	Res. (Bits)	Number of DAC Channels	DAC Architecture	Number ADC Channels	Input Type	Number of GPIOs	Ref Voltage	INL MAX	Package Group	Package Body Size - W x L (mm)	ECCN ¹
AFE11612-SEP	V62/22614	TI Space EP	30	20	43	12	12	String	16	Single-Ended or Fully-differential	8	Internal 2.5V or External	+/- 1LSB	HTQFP	10 x 10	EAR99

¹ECCN information for products that are EAR99 are shown. For up-to-date ECCN information on any product, please email: gtc_eccn-hts-naftateam@list.ti.com.

RF-Sampling Transceivers

Part Number	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT/ RHA	SEL (MeV•cm ² / mg)	Res. (Bits)	Number of DAC Channels	Number of ADC Channels	Number of DUCs per TXe	Number of DDCs per RX	RF Range	Package Group	ECCN ¹
AFE7950-SEP	-	TI Space EP	50	30	43	14	4	6	2	2	0.6-10.2	FCBGA	-

¹ECCN information for products that are EAR99 are shown. For up-to-date ECCN information on any product, please email: gtc_eccn-hts-naftateam@list.ti.com.

Precision ADCs (\leq 10MSPS)

Part Number	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT/ RHA	SEL (MeV•cm ² / mg)	Res. (Bits)	Sample rate (Max) (kSPS)	Number of input Channels	Multi-Ch Configuration	SNR (dB) (\pm LSB)	INL (Max) (\pm LSB)	Input Type	Reference Voltage (V)	Power (Typ) (mW)	Architecture	Packages	ECCN ¹
ADC128S102-SEP	V62/TBD	TI Space EP	30	30	43	12	1000	8	Multiplexed	72	1.1	Single-Ended	Analog supply	2.3	SAR	TSSOP-16	-

High-Speed ADCs (>1GSPS)

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT (krad)	SEL (MeV•cm ² / mg)	Sample Rate (Max) (MSPS)	Res. (Bits)	# of Ch	Analog Input BW (GHz)	SNR (dB)	ENOB (Bits)	SFDR (dB)	Input Range (V _{p-p})	Input Buffer	Power (Typ) (mW)	Type	Pkg. Group
ADC12DJ5200-SEP	-	TI Space EP	30	30	43	10400, 5200	12	1, 2	8	55.6	8.8	65	0.8	Yes	4000	Folding-Interpolating	FCBGA
ADC12QJ1600-SEP	-	TI Space EP	30	30	43	1600	12	4	6	57	9.1	64	0.8	Yes	1900	Folding-Interpolating	FCBGA

High-Speed ADCs (>10MSPS and <1GSPS)

Part Number ¹	Military Spec	Qualification Level	TID Char. (krad)	TID RLAT/ RHA	SEL (MeV•cm ² / mg)	Sample Rate (Max) (MSPS)	Res. (Bits)	# of Ch	Analog Input BW (MHz)	SNR (dB)	ENOB (Bits)	SFDR (dB)	Input Range (V _{p-p})	Input Buffer	Power (Typ) (mW)	Type	Pkg. Group	ECCN ¹
ADC3683-SEP	V62/24602	TI Space EP	50	30	43	65	18	2	400	83.8	13.7	89	3.2	No	186	Serial LVDS	QFN	-
ADC3664-SEP	V62/24601	TI Space EP	50	30	43	125	14	2	700	77.5	12.6	84	3.2	No	200	Serial LVDS	QFN	-

¹EAR99 only pertains to the Engineering Model device, DAC121S101WGMPR. For up-to-date ECCN information contact: gtc_eccn-hts-naftateam@list.ti.com

TI space products – die products

In addition to packaged QMLV products and radiation-tolerant products, TI also offers a variety of space-grade die options, including:

QMLV known good die (KGD): TI fabricates, tests, and qualifies this die product in compliance with MIL-PRF-38535 QMLV with specification in an SMD. RHA versions are available.

TI space-grade KGD: TI qualifies this die product by wafer lots manufactured and tested in accordance with MIL-PRF-38535; it is not included in an SMD, however.

TI Space EP KGD: TI qualifies this die product with TI's radiation-tolerant Space EP flow. See ti.com/SEP.

TI space-grade tested die: TI fabricates this die product on a MIL-PRF-38535-certified manufacturing line; it does not follow the QML manufacturing flow, however, and is tested for DC and functional performance only at ambient temperatures.

Engineering model (EM) die: This die product is intended only for engineering evaluation of its QMLV equivalent. EM die are processed to a noncompliant flow (no burn-in) and tested to a temperature rating of +25°C only. These units are not suitable for qualification, production, radiation testing or flight use. For more information about engineering models, see the “[Texas Instruments Engineering Evaluation Units Versus MIL-PRF-38535 QML Class V Processing](#)” application report.

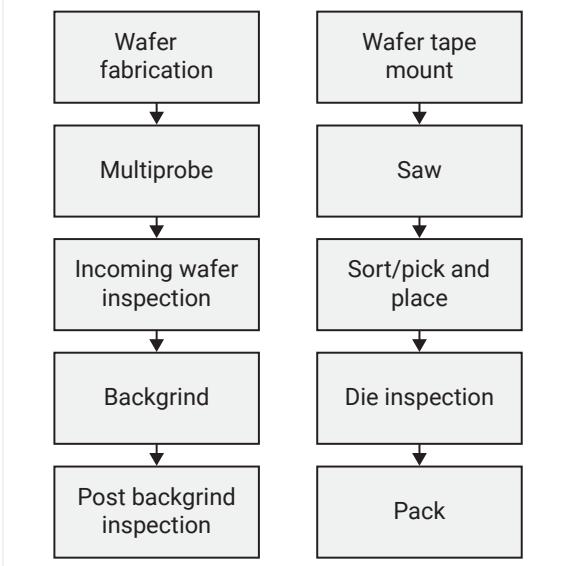
Die products

Generic Part Number	Sub-Family (Part Type)	DLA	Mil Spec (SMD, VID, SS)	TI Orderable Part Number	MIL Orderable Part Number	Device Type Description	Radiation ¹			Temp	ECCN ²
							Max. TID (krad)	RHA: TID RLAT (krad)	RHA: HDR or LDR		
LM111QML-SP	Comparator	5962-00524	LM111-MDE	5962R0052402V9A	QMLV RHA Die	100	100	LDR	-55 to 125°C	EAR99	
LM119QML-SP	Comparator	5962-96798	LM119 MDR	5962R9679801V9A	QMLV RHA Die	100	100	HDR	-55 to 125°C	EAR99	
LM119QML-SP	Comparator	5962-96798	LM119 MDE	5962R9679802V9A	QMLV RHA Die	100	100	LDR	-55 to 125°C	EAR99	
LM139-SP	Comparator	5962-96738	–	5962-9673802V9B	QMLV Die	40	–	–	-55 to 125°C	EAR99	
LM139AQML-SP	Comparator	5962-96738	LM139 MDR	5962R9673801V9A	QMLV RHA Die	100	100	HDR	-55 to 125°C	EAR99	
LM139AQML-SP	Comparator	5962-96738	LM139 MDE	5962R9673802V9A	QMLV RHA Die	100	100	LDR	-55 to 125°C	EAR99	
LM193QML-SP	Comparator	5962-94526	LM193 MDR	5962R9452602V9A	QMLV RHA Die	100	100	HDR	-55 to 125°C	EAR99	
LM193QML-SP	Comparator	5962-94526	LM193 MDE	5962R9452603V9A	QMLV RHA Die	100	100	LDR	-55 to 125°C	EAR99	
LM101AQML-SP	General-Purpose Op Amps	5962-99515	LM101 MDR	–	TI Space-Grade RHA Die	100	50	HDR	-55 to 125°C	EAR99	
LM124-SP	General-Purpose Op Amps	5962-99504	–	5962-9950403V9B	QMLV Die	50	–	–	-55 to 125°C	EAR99	
LM124AQML-SP	General-Purpose Op Amps	5962-99504	LM124 MDR	5962R9950401V9A	QMLV RHA Die	100	100	HDR	-55 to 125°C	EAR99	
LM124AQML-SP	General-Purpose Op Amps	5962-99504	LM124 MDE	5962R9950402V9A	QMLV RHA Die	100	100	LDR	-55 to 125°C	EAR99	
LM158QML-SP	General-Purpose Op Amps	5962-87710	LM158A MDR	5962R8771002V9A	QMLV RHA Die	100	100	HDR	-55 to 125°C	EAR99	
LM158QML-SP	General-Purpose Op Amps	5962-87710	LM158A MDE	5962R8771003V9A	QMLV RHA Die	100	100	LDR	-55 to 125°C	EAR99	
LM6172QML-SP	High-Speed Op Amps (>=50MHz)	5962-95604	LM6172 MDR	5962F9560401V9A	QMLV RHA Die	300	300	HDR	-55 to 125°C	EAR99	
LM6172QML-SP	High-Speed Op Amps (>=50MHz)	5962-95604	LM6172-MDE	5962R9560403V9A	QMLV RHA Die	300	100	LDR	-55 to 125°C	EAR99	
LMP2012QML-SP	Precision Op Amps (Vos<1mV)	5962-06206	LMP2012 MDE	5962L0620602V9A	QMLV RHA Die	50	50	LDR	-55 to 125°C	EAR99	
LMP2012QML-SP	Precision Op Amps (Vos<1mV)	5962-06206	LMP2012 MDR	–	TI Space-Grade RHA Die	50	50	HDR	-55 to 125°C	EAR99	

¹Devices with “–” in the radiation data columns might not have updated detailed radiation data or reports.

²ECCN information for products that are EAR99 are shown. For up-to-date ECCN information on any product, please email: gtc_eccn-hts-naftateam@list.ti.com.

Example flow (QMLV Class V KGD)



Space products – die products (cont'd)

Die products (cont'd)

Generic Part Number	Sub-Family (Part Type)	DLA	TI Orderable Part Number	MIL Orderable Part Number	Device Type Description	Radiation ¹			Temp	ECCN ²
		Mil Spec (SMD, VID, SS)				Max. TID (krad) Characte- rization	RHA: TID RLAT (krad)	RHA: HDR or LDR		
SN54HC08-DIE	AND gate	–	SN54HC08VTD2	–	Tested Die	–	–	–	25°C	EAR99
SN54HC273-DIE	D-type flip-flop	–	SN54HC273VTDG1	–	Tested Die	–	–	–	25°C	EAR99
SN54HC273-DIE	D-type flip-flop	–	SN54HC273VTDG2	–	Tested Die	–	–	–	25°C	EAR99
SN54HC373-DIE	D-type latch	–	SN54HC373VTDG1	–	Tested Die	–	–	–	25°C	EAR99
SN54HC373-DIE	D-type latch	–	SN54HC373VTDG2	–	Tested Die	–	–	–	25°C	EAR99
SN54AC00-DIE	NAND gate	–	SN54AC00VTD1	–	Tested Die	100	–	–	25°C	EAR99
SN54AC00-DIE	NAND gate	–	SN54AC00VTD2	–	Tested Die	100	–	–	25°C	EAR99
SN54AC00-SP	NAND gate	5962-87549	–	5962R8754903V9A	QMLV RHA Die	100	100	HDR	-55 to 125°C	–
SN54AC02-DIE	NOR gate	–	SN54AC02VTD1	–	Tested Die	50	–	–	25°C	EAR99
SN54AC02-DIE	NOR gate	–	SN54AC02VTD2	–	Tested Die	50	–	–	25°C	EAR99

¹Devices with “–” in the radiation data columns might not have updated detailed radiation data or reports.

²ECCN information for products that are EAR99 are shown. For up-to-date ECCN information on any product, please email: gtc_eccn-hts-naftateam@list.ti.com.

Acronyms

ADC	analog-to-digital converter	FIT	failures in time	RHA	radiation hardness assurance
AMU	atomic mass unit	FPGA	field-programmable gate array	RHBD	radiation hardening by design
ASET	analog single-event transient	GCR	galactic cosmic ray	RHBP	radiation hardening by process
ASTM	American Society for Testing and Materials	GEO	geostationary orbit	RLAT	radiation lot acceptance testing
ATE	automated test equipment	GSO	geosynchronous orbit	SAA	South Atlantic Anomaly
BiCMOS	bipolar complementary metal-oxide semiconductor	Gy	gray	SBU	single-bit upset
BJT	bipolar junction transistor	HDR	high dose rate	SEB	single-event burnout
BL	bitline	HEO	high Earth orbit	SEC-DED	single-error correct-double-error detect
BOX	buried oxide	hFE	bipolar transistor gain	SEDR	single-event dielectric rupture
BPSG	boron-doped phosphosilicate glass	IC	integrated circuit	SEE	single-event effect
CAT	computerized axial tomography	IGBT	insulated gate bipolar transistor	SEFI	single-event functional interrupt
CCD	charge-coupled device	LBNL	Lawrence Berkeley National Labs	SEGR	single-event gate rupture
CMEs	coronal mass ejections	LDO	low-dropout regulator	SEL	single-event latch-up
CMOS	complementary metal-oxide semiconductor	LDR	low dose rate	SEM	scanning electron microscope
COTS	commercial off-the-shelf	LEO	low Earth orbit	SEP	solar energetic particles
CT	computer tomography	LET	linear energy transfer	SER	soft-error rate
DAC	digital-to-analog converter	LOCOS	local oxidation of silicon	SET	single-event transient
DBU	double-bit upset	MAAT	metal-oxide semiconductor accelerated anneal test	SEU	single-event upset
DD	displacement damage	MBU	multiple-bit upset	Si	silicon
DDD	displacement damage dose	MCU	microcontroller	SiGe	silicon germanium
DEC-TED	double-error correct-triple-error detect	MEO	medium Earth orbit	SMD	standard microcircuit drawing
DICE	dual interlocked storage cell	MIL-STD	military standard	SOA	safe operating area
DMOSFET	double-diffused metal-oxide semiconductor field-effect transistor	MOS	metal-oxide semiconductor	SoC	system-on-chip
DMR	dual-modular redundant	MOSFET	metal-oxide semiconductor field-effect transistor	SOI	silicon-on-insulator
DRAM	dynamic random-access memory	MUX	multiplexer	SOS	silicon-on-sapphire
DSET	digital single-event transient	ND/PD	neutron dose/proton dose	SRAM	static random-access memory
DTI	deep trench isolation	NIEL	nonionizing energy loss	SRIM	Stopping and Range of Ions in Matter
DUT	device under test	NMOS	N-channel metal-oxide semiconductor	STI	shallow trench isolation
e-h	electron hole	NPN	NPN transistor	TAMU	Texas A&M University
ECC	error correction circuit	NYC	New York City	TDE	time-dependent effect
ELDRS	enhanced low-dose-rate sensitivity	OM	optical microscope	TEM	transmission electron microscope
EMP	electromagnetic pulse	PMOS	P-channel metal-oxide semiconductor	TID	total ionizing dose
ESA	European Space Agency	PNP	PNP transistor	TM	test method
ESCC	European Space Components Coordination	PNPN	PNPN silicon controlled rectifier	TMR	triple-modular redundant
FET	field-effect transistor	QML	Qualified Manufacturers List	TPA	two-photon absorption
		R	read	ULA	ultra-low alpha
		RFID	radio-frequency identification	W	write
				WL	wordline

TI Product Classifications and Qualifications

Rating		Space				
Classification		Space EP	SHP	QMLP	QMLY	QMLV
Production Testing and Documentation Provided	Vendor Item Drawing (VID)	✓	✓	X	X	X
	Standard Microcircuit Drawing (SMD)	X	X	✓	✓	✓
	Process Conformance Report	✓	✓	✓	✓	✓
	Process Conformance Report Content	See Product Page		MIL-PRF-38535 Group A, B, C, D, E		
Manufacturing	Single Controlled Baseline	✓	✓	✓	✓	✓
	Multiple Wafer Lots Per Reel Possible	X	X	X	X	X
	Life Test Per Wafer Lot	X	✓	✓	✓	✓
Packaging	Package Construction	Plastic	Plastic	Plastic - Wirebond or Flip Chip with Overmold	Plastic - Flip Chip w/o Overmold	Hermetic
	Bond Wires	Au	Au	Au	N/A	Al
	Pure Tin (Sn) Lead Finish Possible?	X	X	X	X	X
	>97% Tin (Sn) Inside Package Possible	✓ For Flip Chip				X
	Production Burn-In Required	X	✓	✓	✓	✓
Radiation	Outgassing Tested Per ASTM E595	✓	✓	✓	✓	N/A
	TID Characterization Range (krad/Si)	30 to 50	50 to 300			
	TID Radiation Lot Acceptance Testing (RLAT) Range – RHA (krad/Si)	20, 30 or 50	50, 100 or 300			
SEL Immunity (MeV*cm ² /mg)		≥43	≥60			
Typical Temperature Range		-55–125°C				

Table illustrates typical values for each classification rating. For precise data or detailed information, please refer to the product-specific page.

*BI unless optimization aligned with DLA

TID = Total Ionizing Dose

VID = Vendor Item Drawing

SEL = Single-Event Latch-up

RHA = Radiation Hardness Assured

QML = Qualified Manufacturers List

SMD = Standard Microcircuit Drawing

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